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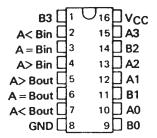
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	TYPICAL	TYPICAL
TYPE	POWER	DELAY
	DISSIPATION	(4-BIT WORDS)
'85	275 mW	23 ns
LS85	52 mW	24 ns
' S85	365 mW	11 ns

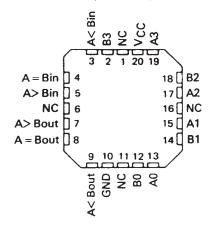
description

These four-bit magnitude comparators perform comparison of straight binary and straight BCD (8-4-2-1) codes. Three fully decoded decisions about two 4-bit words (A, B) are made and are externally available at three outputs. These devices are fully expandable to any number of bits without external gates. Words of greater length may be compared by connecting comparators in cascade. The A > B, A < B, and A = B outputs of a stage handling less-significant bits are connected to the corresponding A > B, A < B, and A = B inputs of the next stage handling more-significant bits. The stage handling the least-significant bits must have a high-level voltage applied to the A = B input. The cascading paths of the '85, 'LS85, and 'S85 are implemented with only a two-gate-level delay to reduce overall comparison times for long words. An alternate method of cascading which further reduces the comparison time is shown in the typical application data.

SN5485, SN54LS85, SN54S85 . . . J OR W PACKAGE SN7485 : . . N PACKAGE SN74LS85, SN74S85 . . . D OR N PACKAGE (TOP VIEW)



SN54LS85, SN54S85 . . . FK PACKAGE (TOP VIEW)

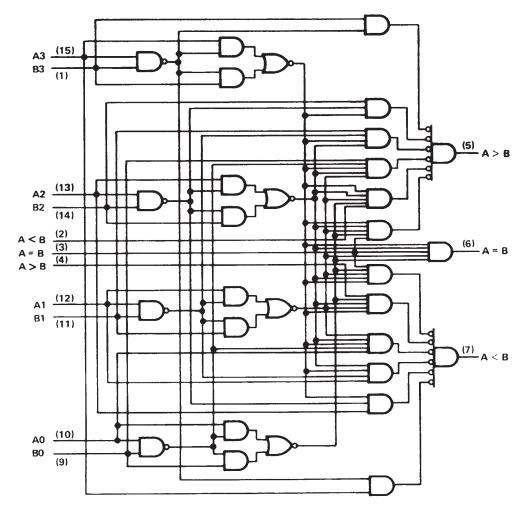


NC - No internal connection

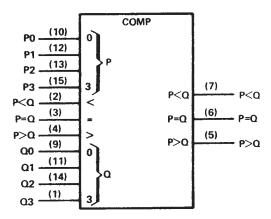
FUNCTION TABLE

	COMP	ARING UTS			CASCADING INPUTS			OUTPUTS	
A3, B3	A2, B2	A1, B1	A0, B0	A > B	A < B	A = B	A > B	A < B	A = 8
A3 > B3	X	×	×	×	Х	×	Н	L	L
A3 < B3	×	×	×	×	X	×	L	н	L
A3 = B3	A2 > B2	×	×	×	X	×	н	L	L
A3 = B3	A2 < B2	×	×	×	X	×	L	Н	L
A3 = B2	A2 = B2	A1 > B1	×	×	X	×	н	L	L
A3 = B3	A2 = B2	A1 < B1	×	×	X	×	L	н	L
A2 = B3	A2 = B2	A1 = B1	A0 > B0	×	X	×	н	L	L
A3 = B3	A2 = B2	A1 = B1	A0 < B0	×	Х	×	L	Н	L
A3 = B3	A2 = B2	A1 = B1	A0 = B0	н	L	L	Н	L	L
A3 = B3	A2 = B2	A1 = B1	AO = BO	L	H	L	L	Н	L
A3 = B3	A2 = B2	A1 = B1	A0 = B0	×	X	Н	L	L	Н
A3 = B3	A2 = B2	A1 = B1	AO = BO	н	н	Ł	L	L	L
A3 = B3	A2 = B2	A1 = B1	A0 = B0	L	L _	L	н	Н	L

logic diagrams (positive logic)



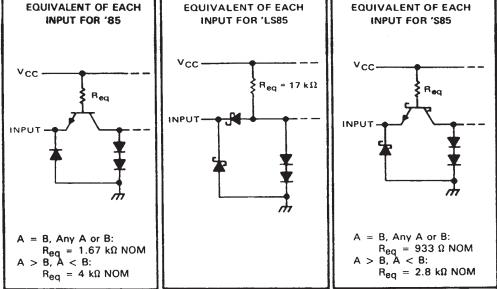
logic symbol[†]

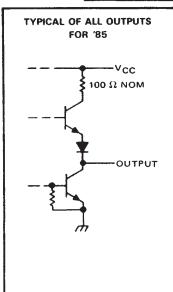


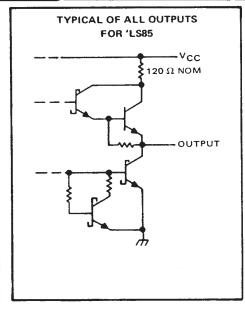
†This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for D, J, N, and W packages.

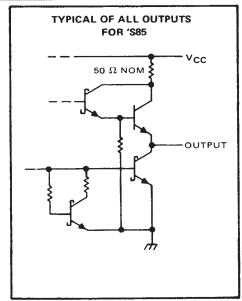


schematics of inputs and outputs









absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

	SN54' SN54S'	SN54LS'	SN74S' 7 7 7 7 5.5 5.5 125 -0 to	SN74LS'	UNIT
Supply voltage, V _{CC} (see Note 1)	7	7	7	7	V
Input voltage	5.5	7	5.5	7	V
Interemitter voltage (see Note 2)	5.5		5.5		V
Operating free-air temperature range	- 55	to 125	-0	to 70	°C
Storage temperature range	-65	to 150	- 65	to 150	°C

NOTES: 1. Voltage values, except interemitter voltage, are with respect to network ground terminal.

2. This is the voltage between two emitters of a multiple-emitter input transistor. This rating applies to each A input in conjunction with its respective B input of the '85 and 'S85.



SN5485, SN54LS85, SN54S85 SN7485, SN74LS85, SN74S85 4-BIT MAGNITUDE COMPARATORS

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recommended operating conditions

		SN5485	5		SN7485		
	MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Supply voltage, V _{CC}	4.5	5	5.5	4.75	5	5.25	٧
High-level output current, IOH			-400			-400	μΑ
Low-level output current, IOL			16			16	mA
Operating free-air temperature, TA	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER		TE	ST CONDIT	IONS†		MIN	TYP‡	MAX	UNIT
ViH	High-level input voltage						2			V
VIL	Low-level input voltage								0.8	٧
VIK	Input clamp voltage		V _{CC} = MIN,		1 = -1:	2 mA			-1.5	٧
Vон	High-level output voltage		V _{CC} = MIN, V _{IL} = 0.8 V,		V _{IH} = 2	2 V, -400 μA	2.4	3,4		٧
VOL	Low-level output voltage		V _{CC} = MIN, V _{IL} = 0.8 V,		V _{IH} = 2			0.2	0.4	٧
11	Input current at maximum inp		V _{CC} = MAX,		V _I = 5.5	5 V			1	mA
ЧН	High-level input current	A < B, A > B inputs	V _{CC} = MAX,	•	V ₁ = 2.4	1 V			40 120	μА
1 ₁ L	Low-level input current	A < B, A > B inputs	V _{CC} = MAX,		V _I = 0.4	ı v			-1.6 -4.8	mA
los	Short-circuit output current§	<u> </u>	V _{CC} = MAX,	V _O = 0		SN5485 SN7485	-20 -18		-55 -55	mA
¹ CC	Supply current		V _{CC} = MAX,	See Note 4				55	88	mA

 $^{^\}dagger$ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

NOTE 4: I_{CC} is measured with outputs open, A = B grounded, and all other inputs at 4.5 V.

switching characteristics, VCC = 5 V, TA = 25°C

PARAMETER	FROM INPUT	TO OUTPUT	NUMBER OF GATE LEVELS	TEST CONDITIONS	MIN	TYP	MAX	UNIT
		·	1			7		
	A A B -	A < B, $A > B$	2			12		
^t PLH	Any A or B data input		3]		17	26	ns
		A = B	4]		23	35	
			1			11		
		A < B, A > B	2	C_L = 15 pF, R_L = 400 Ω , See Note 5		15		
^t PHL	Any A or B data input	,	3			20	30	ns
		A = B	4			20	30	
^t PLH	A < B or A = B	A > B	1	See Note 5		7	11	ns
tPHL	A < B or A = B	A > B	1	1		11	17	ns
t _{PLH}	A = B	A = B	2			13	20	ns
^t PHL	A = B	A = B	2			11	17	ns
[†] PLH	A > B or A = B	A < B	1			7	11	ns
tPHL.	A > B or A = B	A < B	1	<u> </u>		11	17	пѕ

tpLH = propagation delay time, low-to-high-level output

NOTE 5: Load circuits and voltage waveforms are shown in Section 1.



 $^{^{\}ddagger}$ All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}$ C.

[§]Not more than one output should be shorted at a time.

tpHL = propagation delay time, high-to-low-level output

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recommended operating conditions

	S	N54LS	35	S	N74LS	35	UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Supply voltage, V _{CC}	4.5	5	5.5	4.75	5	5.25	V
High-level output current, IOH			-400			-400	μА
Low-level output current, IQL			4			8	mA
Operating free-air temperature, TA	-55		125	0		70	°c

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

				t	S	N54LS8	15	S	N74LS8	15	
	PARA	METER	TEST CON	IDITIONS [†]	MIN	TYP‡	MAX	MIN	TYP [‡]	MAX	UNIT
VIH	High-level input	voltage			2		-	2			V
VIL	Low-level input	voltage					0.7			0.7	٧
VIK	Input clamp vol	tage	VCC = MIN,	I _I = -18 mA			-1.5			-1.5	٧
Vон	High-level outpu	ıt voltage	V _{CC} = MIN, V _{IL} = V _{IL} max,	V _{1H} = 2 V, I _{OH} = -400 μA	2.5	3.4		2.7	3.4		٧
		_	V _{CC} = MIN,	IOL = 4 mA		0.25	0.4		0.25	0.4	v
VOL	Low-level output	it voltage	V _{IH} = 2 V, V _{IL} = V _{IL} max	1 _{OL} = 8 mA					0.35	0.5	Ľ
	Input current	A < B, A > B inputs					0.1			0.1	mA
11	at maximum input voltage	all other inputs	V _{CC} = MAX,	V ₁ = 7 V			0.3			0.3	IIIA
	High-level	A < B, A > B inputs	.,	W = 2.7.V			20			20	μА
ΉН	input current	all other inputs	V _{CC} = MAX,	V ₁ = 2.7 V			60			60	J # 1
	Low-level	A < B, A > B inputs	1/ - MAN	V ₁ = 0.4 V			-0.4			-0.4	mA
HL	input current	all other inputs	V _{CC} = MAX,	V = 0.4 V			-1.2			-1.2	
los	Short-circuit ou	tput current §	V _{CC} = MAX		-20		-100	-20		-100	mA
Icc	Supply current		VCC = MAX,	See Note 4		10.4	20		10.4	20	mA

[†]For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

NOTE 4: I_{CC} is measured with outputs open, A = B grounded, and all other inputs at 4.5 V.

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

DADAMETED¶	FROM	ТО	NUMBER OF	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
PARAMETER¶	INPUT	OUTPUT	GATE LEVELS	TEST COMBITTORS					
			1			14		1	
		A < B, A > B	2			19		ns	
^t PLH	Any A or B data input		3			24	36		
		A = B	4	1		27	45		
		A < B, A > B	1			11			
	Any A or B data input		A < B, A > B	2	0 15 5		15		ns
^t PHL			3	$C_L = 15 pF$		20	30] "	
				A = B	4	$R_L = 2 k\Omega$		23	45
tPLH	A < B or A = B	A > B	1	See Note 5		14	22	ns	
tPHL	A < B or A = B	A > B	1			11	17	ns	
tPLH	A = B	A = B	2			13	20	ns	
tPHL	A = B	A = B	2			13	26	ns	
tPLH	A > B or A = B	A < B	1	1		14	22	ns	
tPHL	A > B or A = B	A < B	1	1		11	17	ns	

 $[\]P_{tPLH}$ = propagation delay time, low-to-high-level output

NOTE 5: Load circuits and voltage waveforms are shown in Section 1.



 $[\]ddagger$ All typical values are at V_{CC} = 5 V, T_A = 25°C. \$Not more than one output should be shorted at a time, and duration of the short-circuit should not exceed one second.

tpHL = propagation delay time, high-to-low-level output

SN5485, SN54LS85, SN54S85 SN7485, SN74LS85, SN74S85 4-BIT MAGNITUDE COMPARATORS

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recommended operating conditions

		SN54S8	5	SN74S85			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	UNII
Supply voltage, V _{CC}	4.5	5	5.5	4.75	5	5.25	V
High-level output current, IOH			-1			-1	mA
Low-level output current, IOL			20			20	mA
Operating free-air temperature, TA	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	l	TES	T CONDITIONS	;†	MIN	TYP‡	MAX	UNIT
VIH	High-level input voltage					2			٧
VIL	Low-level input voltage							8.0	٧
VIK	Input clamp voltage		VCC = MIN,	I ₁ = -18 mA				-1.2	V
			V _{CC} = MIN,	V _{IH} = 2 V,	SN54S85	2.5	3.4		v
νон	High-level output voltage		$V_{IL} = 0.8 V$	1 _{OH} = -1 mA	SN74S85	2.7	3.4		
.,			V _{CC} = MIN,	V _{IH} = 2 V,				0.5	V
VOL	Low-level output voltage		VIL = 0.8 V,	1 _{OL} = 20 mA				0.5	
1,	Input current at maximum input	t voltage	VCC = MAX,	V ₁ = 5.5 V				1	mA
	11:	A < B, A > B inputs	V _{CC} = MAX,	V 27 V				50	μА
ин	High-level input current	all other inputs	VCC - MAA,	VI - 2.7 V				150	
<u> </u>		A < B, A > B inputs	VCC = MAX,	V. = 0.5.V				-2	mA
11L	Low-level input current	all other inputs	VCC - WAX,	V1 - 0.5 V				-6	1111/
Ios	Short-circuit output current §		V _{CC} = MAX			-40		-100	mA
			V _{CC} = MAX,	See Note 4			73	115	
'cc	Supply current		V _{CC} = MAX, See Note 4	T _A = 125°C,	SN54S85W			110	mA

[†]For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

NOTE 4: I_{CC} is measured with outputs open, A = B grounded, and all other inputs at 4.5 V.

switching characteristics, VCC = 5 V, TA = 25°C

PARAMETER¶	FROM INPUT	TO OUTPUT	NUMBER OF GATE LEVELS	TEST CONDITIONS	MIN TYP	MAX	UNIT	
			1		5		}	
		A < B, A > B	2		7.5		ns	
^t PLH	Any A or B data input		3		10.5	16] ""	
		A = B	4		12	18		
			1		5.5			
		A < B, A > B	A < B, A > B	2	0 45.5	7		ns
^t PHL	Any A or B data input	•	3	C _L = 15 pF,	11	16.5	115	
		A = B	4	R _L = 280 Ω , See Note 5	11	16.5		
tPLH	A < B or A = B	A > B	1	See Note 5	5	7.5	ns	
tPHL	A < B or A = B	A > B	1		5.5	8.5	ns	
tPLH	A = B	A = B	2		7	10.5	ns	
tPHL	A = B	A = B	2		5	7.5	ns	
tPLH	A > B or A = B	A < 8	1		5	7.5	ns	
tPHL	A > B or A = B	A < B	1		5.5	8.5	ns	

 $[\]P_{tPLH}$ = propagation delay time, low-to-high-level output

NOTE 5: Load circuits and voltage waveforms are shown in Section 1.

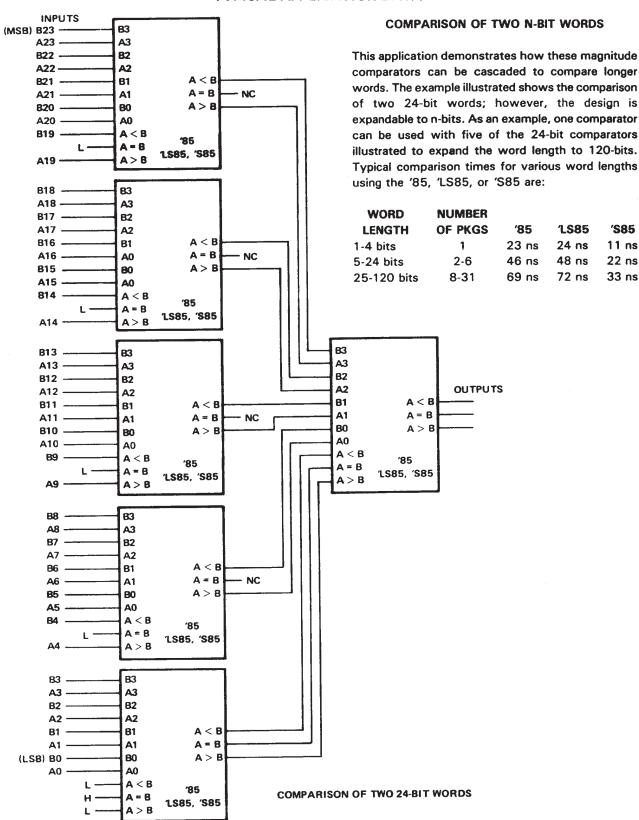


 $[\]ddagger$ All typical values are at $V_{CC} = 5 \text{ V}$, $T_{A} = 25^{\circ} \text{C}$.

[§]Not more than one output should be shorted at a time, and duration of the short-circuit should not exceed one second.

tpHL = propagation delay time, high-to-low-level output

TYPICAL APPLICATION DATA



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